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Schuster, Noah Alexandra

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VRIJE UNIVERSITEIT

**Bias in Regression Analysis**  
Problems and Solutions

ACADEMISCH PROEFSCHRIFT

ter verkrijging van de graad Doctor of Philosophy aan  
de Vrije Universiteit Amsterdam,  
op gezag van de rector magnificus  
prof.dr. J.J.G. Geurts,  
in het openbaar te verdedigen  
ten overstaan van de promotiecommissie  
van de Faculteit der Geneeskunde  
op woensdag 9 november 2022 om 13.45 uur  
in een bijeenkomst van de universiteit,  
De Boelelaan 1105

door  
Noah Alexandra Schuster  
geboren te Amsterdam

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